

10/533238

<b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  (PTO-1449)				ATTY. DOC. NO. IPA-006		U.S. APPLICATION NO. Not yet assigned	
				APPLICANT Akira NAKASHIMA et al.			
				FILING DATE herewith		GROUP	
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						Yes	No
<b>OTHER ART (including Author, Title, Date, Pertinent Pages, Etc.)</b>							
NY	Patent Abstract of Japan; Publication No.: 2003-249495; Publication Date: 09/05/2003; Applicant: ASAHI KASEI CORP						
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	Patent Abstract of Japan; Publication No.: 2000-349083; Publication Date: 12/15/2000; Applicant: NIPPON ASM KK						
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EXAMINER Victor Yevsikov/ (04/06/2007)			DATE CONSIDERED				

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**INFORMATION DISCLOSURE  
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APPLICATION**  
(PTO-1449)

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U.S. PATENT  
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**Akira Nakashima et al.**

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2891

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**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**


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*V. Yevsikov*  
Victor Yevsikov/ (04/06/2007)

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